



**INTERNATIONAL  
TEST CONFERENCE  
2008**  
Oct. 28 – Oct. 30, 2008  
Santa Clara Convention Center  
Santa Clara, CA, USA

# CALL FOR PARTICIPATION Corporate Presentations

*The Cornerstone of Test Week™*  
Test Week: Oct. 26 – Oct. 31, 2008

## Corporate Presentations

International Test Conference is the world's premier conference dedicated to the electronic test of devices, boards and systems-covering the complete cycle from design verification, test, diagnosis, and failure analysis, back to process and design for yield improvement.

ITC is offering conference exhibitors and prime corporate supporters (diamond, platinum, gold, and silver) the opportunity to give technical presentations in a track parallel to the technical sessions. These presentations will be listed in the conference program along with the technical sessions, and should be targeted to the ITC technical audience. The corporate presentation sessions will differ from standard ITC presentations in that product names and logos may be mentioned explicitly. Typical content could include product descriptions, case studies, best practices, and testimonials.

Presentation opportunities are only available to registered ITC exhibitors and corporate supporters. Space will be allocated on a first-come, first-served basis, with one 30-minute time slot per 20-minute presentation. Attendance at the sessions will be open to all conference and exhibit attendees. Company representatives will be free to hand out literature at the session.

Proposals should be in summary form (see below) and will be reviewed for content by the ITC program committee in order to ensure high quality. Submissions must include:

- Title of presentation.
- Name, affiliation, mailing address, e-mail address, telephone and fax number of each author.
- Designation of the presenter(s). ITC will communicate with the presenter(s).
- An abstract of 25 words or less to be included in the Advance Program and Conference Guide.

**Please note that all deadlines are firm.**

**Submission Deadline: August 1, 2008**

**Initial Presentation Deadline and Final Title and Abstract Deadline: August 25, 2008**

**Final Presentation Deadline: September 15, 2008**

**All submissions and presentations must be in electronic format. Prospective authors should read the detailed instructions regarding formats and submission requirements that are available on the ITC Web site at: <http://www.itctestweek.org>**

**For further information, check the ITC Web page or contact:**

International Test Conference,  
Washington, DC, USA  
Tel: +1 202.973.8665  
Fax: +1 202.331.0111  
Email: [itc@courtesyassoc.com](mailto:itc@courtesyassoc.com)



*ITC Invites submissions on the latest techniques for testing and diagnosing ICs, boards and systems.*

### Conference Focus Topics:

Adaptive Test  
BIST or Embedded Test-Chip and Board  
Bring-up Test and Debug  
Design and Test for Reliability  
Experiments and Case Studies  
High-Speed I/O Test  
High-Speed Digital Test  
Low-Cost Test/ATE  
On-Chip Test Compression  
RF Testing  
Test Data Analysis  
Test and Design for Manufacturability  
Test for Nanometer Technologies  
Test Resource Partitioning

### Hot Topics:

Board and System Test  
Defect-based Testing  
Innovative Industrial Test Practices  
On-line Test  
Power Issues in Test  
Volume Diagnosis and Yield Learning

### General Chair:

Douglas Young  
[dyoung@svprobe.com](mailto:dyoung@svprobe.com)

### Exhibits Chair:

Ron Press  
[Ron.Press@mentor.com](mailto:Ron.Press@mentor.com)

### Corporate Track Chair:

Erik Volkerink  
[Erik.Volkerink@verigy.com](mailto:Erik.Volkerink@verigy.com)